

**Notice of References Cited**

Application/Control No.

09/934,468

Applicant(s)/Patent Under  
Reexamination  
OKA ET AL.

Examiner

Hae Moon Hyeon

Art Unit

2839

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,877,944 /	03-1999	Onizuka, Takahiro	439/76.2
	B	US-6,126,457 /	10-2000	Smith et al.	439/76.2
	C	US-6,224,397 /	05-2001	Nakamura, Masayoshi	439/76.2
	D	US-6,270,360 /	08-2001	Yanase, Takeshi	439/76.2
	E	US-6,309,226 /	10-2001	Nakatani, Eiji	439/76.2
	F	US-6,354,846 /	03-2002	Murakami, Masakazu	439/76.2
	G	US-2001/0012736 A1 /	08-2001	Miyajima et al.	439/76.2
	H	US-5578008 /	11-1996	Hara	604/96.01
	I	US-4439801 /	03-1984	Fajt	361/55
	J	US-4415830 /	11-1983	Pugh et al.	313/331
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.